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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE 1.1 <u>Scope</u>. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices". 1.2 Part number. The complete part number shall be as shown in the following example: 82036 Device type Drawing number Case outline Lead finish per (1.2.1)(1.2.2)MIL-M-38510 1.2.1 Device types. The device types shall identify the circuit function as follows: Device type Generic number Circuit function 01 0P-07A Operational amplifier, ultra low offset Operational amplifier, low offset 02 OP-07 1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows: Outline letter Case outline A-1 (8-lead, .370" x .185"), can D-4 (8-lead, .405" x .310" x .200"), dual-in-line package C-2 (20-terminal, .358" x .358" x .100"), square chip carrier G Ρ 2 package 1.3 Absolute maximum ratings. +22 V dc ±V<sub>CC</sub> ±30 V dc Output short circuit duration-------1/ <sup>17</sup> +300°C -65°C to +150°C Thermal resistance, junction-to-case  $(\theta_{JC}) = - - - -$ MIL-M-38510, appendix C 330 mW at  $T_A = +125^{\circ}C$ 400 mW at  $T_A = +125^{\circ}C$ Thermal resistance, junction-to-ambient  $(\theta_{JA})$ : Cases P and 2------120°C/W 150°C/W 1.4 Recommended operating conditions. Supply voltage range (V<sub>CC</sub>) - - - - - - - - - - +5.0 V dc to ±20.0 V dc Ambient operating temperature range (T<sub>A</sub>) - - - - - - - -55  $^\circ$ C to +125  $^\circ$ C Output may be shorted to ground indefinitely at  $V_S = \pm 15 V$ ,  $T_A = \pm 25^{\circ}C$ . Temperature and supply voltages must be limited to ensure dissipation rating is not exceeded. 17 2/ Must withstand the added P<sub>D</sub> due to short circuit test, e.g., I<sub>DS</sub>. STANDARDIZED SIZE Α MILITARY DRAWING 82036 DEFENSE ELECTRONICS SUPPLY CENTER **REVISION LEVEL** SHEET DAYTON, OHIO 45444

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2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standard</u>. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 <u>Terminal connections and logic diagrams</u>. The terminal connections and logic diagrams shall be as specified on figure 1.

3.2.2 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.

3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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Test	  Symbol	$\sim 1000000000000000000000000000000000000$	     Group A	 	Lim 01	its	02	   
		$ \begin{array}{c} -55 \ \text{C} < \text{T}_{\text{A}} < +125 \ \text{C} \\ V_{\text{CC}} = \pm 15 \ \text{V}_{\text{,}} \text{ unnulled,} \\ V_{\text{CM}} = 0 \\ I \\ (unless otherwise specified) \end{array} $	subgroups	Min	<b>F</b>	Min 		
Input offset voltage	V <sub>I0</sub>	<u>1/2/</u>	1	-25	25	  -75	75	μγ 
		2/	2,3	-60	60	  -200 	200	Ι   μΨ 
Input offset voltage temperature sensitivity		3/	2,3	6   	.6     	-1.3   	1.3   	μV/°(     
Input bias current	+IIB		1	-2	2	-3	3	nA
			2,3	-3	3	-6	6	nA
	-I <sub>IB</sub>		1	-2	2	-3	3	nA
			2,3	   _4	4	   -6 	6	   nA 
Input offset current	+I10		1	-2	2	-2.8	2.8	nA
			2,3	_4	4	  -5.6  	5.6	nA
Power supply rejection ratio	+PSRR	$V_{CC}^{+} = 20 V to 5 V, V_{CC}^{-} = -15$	V 1		10		10	μV/V
	I-PSRR	$V_{CC}^{+} = 15 V$ , $V_{CC}^{-} = -20 V$ to $-5$	V   1		10		10	μ <b>V/V</b>
	+PSRR	$V_{CC}^+ = 20 V \text{ to } 5 V, V_{CC}^- = -15$	V   2,3		20		20	μ <b>V/V</b>
	I-PSRR	$V_{CC}^{+} = 15 V$ , $V_{CC}^{-} = -20 V$ to $-5$	V 2,3		20		20	μ <b>ν/</b> γ
See footnotes a	t end of	table.						
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Test	    Symbol		nditions [A_< +125°C			Lim	its	~~~	Turt
iest	   	$V_{CC} = \frac{1}{V_{CL}}$	$A \leq +125 C$ V, unnulled, A = 0 erwise specified)	Group A  subgroups   	   Min	01     Max 	    Min 	02    Max	TUni T   
Common mode rejection	CMRR	V <sub>CM</sub> = ±10 V		1	110		110	†   	i i d
ratio		V <sub>CM</sub> ≃ ±13 V		2,3	106		106		d
Output short circuit	IOS(+)	   t <u>&lt;</u> 25 ms <u>4</u> /		1, 2, 3	  -60	   	  -60 	   	m. 
current	I <sub>OS(-)</sub>			1, 2, 3		   50 	 	50	   m. 
Supply current		   		1		4	   	4	   m/
		 		2,3	   	5	   	5	i m/
Output voltage swing (minimum)	V <sub>OP</sub>	R <sub>L</sub> = 1 kΩ		4, 5, 6	-10	10	-10	10	V
		R <sub>L</sub> = 2000Ω		4, 5, 6	-12	12	-12	12	v
Open loop voltage gain ( (single	Avs	$T_{A} = +25^{\circ}C = \frac{5}{2}$		4	300		200	   	V/r
ended)		5	/	5,6	200		150		V/n
<ul> <li>2/ lesting will</li> <li>3/ Shall be gu</li> <li>4/ Continuous maximum pov</li> <li>5/ V<sub>OUT</sub> = 0 V</li> <li>3.5 Certification</li> <li>3.5 Certification</li> <li>3.5 Certification</li> <li>3.6 Certification</li> </ul>	Il occur Jaranteed short ci ver dissi to +10 \ ite of co isted as iC-ECS pr product m ate of co	at least 250 ms a d if not tested, t ircuit limits are ipation cannot be / for $A_{VS}(+)$ and V ompliance. A cert an approved sour tior to listing as neets the requirem	g steady-life test fter application c o the specified pa considerably less exceeded. DUT = 0 to -10 for ificate of complia ce of supply in 6. an approved sourc ents of MIL-STD-88 tificate of confor f microcircuits de	of power. rameters. than the indic Ays(-). RL nce shall be a 4. The certif e of supply sh 3 (see 3.1 her mance as requi	cated 1 = 2000 require ficate hall st rein) a	2. ed from of com ate th and the	n a ma nplian nat th e requ	anufac nce ne uireme	ture: ents
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۲ Device types 01 and 02 Case 2 Vos Vos TRIM NC TRIM NC NC 19 3 2 20 T 18 NC NC 4 17 Vcc+ -IN 5 16 NC NC 6 15 OUTPUT + IN 7 14 NC NC 8 I3 NC 9 NC 12 10 П VCC- NC NC FIGURE 1. Terminal connections and logic diagrams - Continued. 1 **STANDARDIZED** SIZE Α 82036 **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER **REVISION LEVEL** SHEET DAYTON, OHIO 45444 С 7

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3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with NIL-STD-883 (see 3.1 herein).

3.8 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^{\circ}C$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

**4.3** <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 7, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
- 4.3.2 Groups C and D inspections.
  - a. End-point electrical parameters shall be as specified in table II herein.
  - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
    - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
    - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test req	uirements.
MIL-STD-883 test requirements	Subgroups   (per method   5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 4
Group A test requirements (method 5005)	1, 2, 3, 4, 5, 6
Groups C and D end-point electrical parameters (method 5005)	1** and table III

\* PDA applies to subgroup 1 excluding V<sub>IO</sub>.
 \*\* Table III limits used for V<sub>IO</sub> and ±I<sub>IB</sub> in place of table I limits.

	-			<b>c, - i</b> cc	= ±15 V, \		_		
Test	End-po	int limit	ce 01	Delta	End pot	Device 02		Tta I	Unit
	Min	Max	Min	Max	   Min	Max	   Min	Max	
۷ <sub>IO</sub>	- 100	   +100 	   _75 	75	   _175	+175	-100		μV
±IIB	3	+3	-1	1	-4.5	+4.5	1.5	1.5	nA

TABLE III.	Group C	end-point	electrical	parameters.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

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6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

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6.2 <u>Replaceability</u>. Replaceability is determined as follows:

- a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/13501BXX and M38510/13502BXX.

6.3 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.4 <u>Approved source of supply</u>. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5) has been submitted to DESC-ECS.

Military drawing part number	Vendor   CAGE   number	Vendor   similar part   number <u>1</u> / 	Replacement military specification part number
8203601GX <u>2</u> /	06665 07933 64155 54186	OP07AJ   OP-07AT/883B   OP-07AH/883   MPOP07AJ/883	M38510/13501BGX
8203601PX <u>2</u> /	06665 07933 64155 54186	CP07AZ OP-07ADE/883B OP-07AJ8/883 MP0P07AZ/883	M38510/13501BPX
82036012X	06665 54186	OPO7ARC MPOPO7AL/883	M38510/13501B2X
8203602GX <u>2</u> /	06665 07933 64155 54186	0P07J 0P-07T/883B 0P-07H/883 MP0P07J/883	M38510/13502BGX
8203602PX <u>2</u> /	06665 07933 64155 54186	0P07Z 0P-07DE/883B 0P-07J8/883 MP0P07Z/863	M38510/13502BPX
32036022X	06665 54186	0P07RC MP0P07L/883	M38510/13502B2X

2/ Inactive for new design, use QPL-M38510 product.

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Vendor CAGE number		Vendor nar and addres		
06665		Precision Mond 1500 Space Par Santa Clara, (	rk Drive	corporated
07933		Raytheon Compa Semiconductor 350 Ellis Stre P.0 Box 7016 Mountain View,	Division eet	5-7016
64155		Linear Technol 1630 McCarthy Milptas, CA	Boulevard	ration
54186		Micro Power Sy 3100 Alfred St Santa Clara, C	reet	
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